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<b>FORM 149-E</b> <b>PATENT &amp; TRADEMARK OFFICE</b> <b>MAY 31 2005</b>	<b>INFORMATION DISCLOSURE STATEMENT</b>		Docket Number: KOL.198.WUS	Application Number: 10/552,403
	<b>IN AN APPLICATION</b>		Applicant: Koivukangas et al.	
	(Use several sheets if necessary)		Filing Date: 10/07/2005	Group Art Unit: 2829

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
EK	5,481,186	01/02/1996	Heutmaker et al.	—	—	
↓	5,889,837	03/30/1999	Sands	—	—	
↓	6,118,982	09/12/2000	Ghisler et al.	—	—	
↓	6,404,293	06/11/2002	Darabi et al.	—	—	

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
EK	0 525 941	02/03/1993	EP	—	—	X	
↓	0 759 680 A1	02/26/1997	EP	—	—	X	
↓	0 825 734 A2	02/25/1998	EP	—	—	X	
↓	198 41 470 A1	04/13/2000	DE	—	—		X
↓	01/63827 A1	08/30/2001	WO	—	—	X	

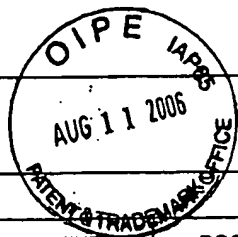
  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
EK	1997	Anthony P. Ambler, Moshe Ben Bassat and Louis Y. Ungar, "Economics of Diagnosis" Autotestcon, 97. 1997 IEEE Autotestcon Proceedings Ahanheim, CA, USA Sept. 22-25 1997, New York, NY USA, IEEE, pages 435 - 445. XP010253057 ISBN: 0-7803-4162-7.
↓	1999	Yervant Zorian, "Built-In-Self-Test", Microelectronic Engineering, Elsevier Publishers, BV., Amsterdam, NL, Vol. 49, no. 1-2, November 1999, pages 135-138. XP004182057, ISSN: 0167-9317.
↓	2001	Louis Y. Ungar et al., "IEEE-1149.X Standards: Achievements vs. Expectations", 2001 IEEE Autotestcon Proceedings. IEEE Systems Readiness Technology Conference. Autotestcon 2001, Valley Forge, PA, Aug. 20-23, 2001, IEEE Autotestcon Proceedings: IEEE Systems Readiness Technology Conference, New York, NY: IEEE, US, Vol. Conf. 37, XP 010556098, ISBN: 0-7803-7094-5.
↓	2001	Yue-Tsang Chen et al.: "Test Waveform Shaping in Mixed Signal Test Bus by Pre-Equalization", VLSI Test Symposium, 19 <sup>th</sup> IEEE Proceedings on VTS 2001 Apr 29 - 2001 May 3, Piscataway, NJ, USA, IEEE, 29 April 2001 (2001-04-29), pages 260-265, XP010542396 ISBN: 0-7695-1122-8.
↓	1994	Lu Y et al.: "Structure and Metrology for a Single-wire Analog Testability Bus", in Proceedings of the International Test Conference, Washington, Oct. 2 - 6, 1994, New York, IEEE, US, 2 October 1994 (1994-10-02), pages 919-928, XP000520055 ISBN: 0-7803-2103-0.

EXAMINER /Ernest Karlsten/	DATE CONSIDERED 10/12/2006
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.	

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<b>FORM 1449*</b> <b>INFORMATION DISCLOSURE STATEMENT</b>  <b>IN AN APPLICATION</b> (Use several sheets if necessary)	Docket Number: KOL.198.WUS	Application Number: 10/552,403
	Applicant: Koivukangas et al.	
	Filing Date: 10/07/2005	Group Art Unit: 2829



U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
EK	December 2000	Gielen et al., "Computer-Aided Design of Analog and Mixed-Signal Integrated Circuits", Proceedings of the IEEE, Vol. 88, No. 12, December 2000, pp. 1825-1852.
EK	May 1993	Toner et al., "Towards Built-In-Self-Test for SNR Testing of a Mixed-Signal IC", Proceedings of the International Symposium on circuits and Systems (ISCS), Chicago, May 3-6, 1993, IEEE, US, vol.2, pp. 1599-1602.

EXAMINER	/Ernest Karlsen/	DATE CONSIDERED	10/12/2006
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.			